

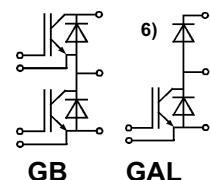
Absolute Maximum Ratings		Values	Units		
Symbol	Conditions¹⁾				
V _{CES}		1200	V		
V _{CGR}	R _{GE} = 20 kΩ	1200	V		
I _C	T _{case} = 25/80 °C	260 / 180	A		
I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	520 / 360	A		
V _{GES}		± 20	V		
P _{tot}	per IGBT, T _{case} = 25 °C	1040	W		
T _j , (T _{stg})		-40 ... +150 (125)	°C		
V _{isol}	AC, 1 min.	2500	V		
humidity	IEC 60721-3-3	class 3K7/IE32			
climate	IEC 68 T.1	40/125/56			
Inverse Diode and FWD of type „GAL“ ^{6 8)}					
I _F = -I _C	T _{case} = 25/80 °C	200 / 160	A		
I _{FM} = -I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	520 / 360	A		
I _{FSM}	t _p = 10 ms; sin.; T _j = 150 °C	1450	A		
I ² t	t _p = 10 ms; T _j = 150 °C	10 500	A ² s		
Characteristics					
Symbol	Conditions¹⁾	min.	typ.	max.	Units
V _{(BR)CES}	V _{GE} = 0, I _C = 4 mA	≥ V _{CES}	—	—	V
V _{GE(th)}	V _{GE} = V _{CE} , I _C = 6 mA	4,5	5,5	6,5	V
I _{CES}	V _{GE} = 0	—	0,2	0,4	mA
	T _j = 25 °C	—	12	—	mA
	V _{CE} = V _{CES}	—	—	0,3	μA
I _{GES}	T _j = 125 °C	—	—	—	
V _{CEsat}	V _{GE} = 20 V, V _{CE} = 0	—	—	—	
V _{CEsat}	I _C = 150 A	2,1(2,4)	2,45(2,85)	—	V
V _{CEsat}	V _{GE} = 15 V;	—	—	—	V
I _C = 200 A	T _j = 25 (125) °C	2,5(3,0)	—	—	V
g _{fs}	V _{CE} = 20 V, I _C = 150 A	62	—	—	S
C _{CHC}	per IGBT	—	—	350	pF
C _{ies}	V _{GE} = 0	—	11	15	nF
C _{oes}	V _{CE} = 25 V	—	1,6	2	nF
C _{res}	f = 1 MHz	—	0,8	1	nF
L _{CE}		—	—	25	nH
t _{d(on)}	V _{CC} = 600 V	—	70	—	ns
t _r	V _{GE} = +15 V / -15 V ³⁾	—	55	—	ns
t _{d(off)}	I _C = 150 A, ind. load	—	490	—	ns
t _f	R _{Gon} = R _{Goff} = 7Ω	—	65	—	ns
E _{on}	T _j = 125 °C	—	26	—	mWs
E _{off}		—	23	—	mWs
Inverse Diode and FWD of type „GAL“ ^{6 8)}					
V _F = V _{EC}	I _F = 150 A	—	2,0(1,8)	2,5	V
V _F = V _{EC}	V _{GE} = 0 V;	—	2,25(2,05)	—	V
V _{TO}	I _F = 200 A	—	1,1	1,2	V
r _t	T _j = 125 °C ²⁾	—	—	7	mΩ
I _{RRM}	T _j = 125 °C ²⁾	—	87	—	A
Q _{rr}	I _F = 150 A; T _j = 125 °C ²⁾	—	19	—	μC
Thermal characteristics					
R _{thjc}	per IGBT	—	—	0,12	°C/W
R _{thjc}	per diode	—	—	0,23	°C/W
R _{thch}	per module	—	—	0,05	°C/W

SEMITRANS® M Low Loss IGBT Modules

SKM 195 GB 124 DN
SKM 195 GAL 124 DN



SEMITRANS 2N (low inductance)



Features

- N channel, homogeneous Silicon structure NPT-IGBT (Non punch through)
- Low saturation voltage
- Low inductance case
- Low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 * I_{cnom}
- Fast & soft inverse CAL diodes⁸⁾
- Without hard mould
- Large clearance (10 mm) and creepage distances (20 mm)

Typical Applications

- Switching (not for linear use)
- Switched mode power supplies
- DC servo and robot drives
- Inverters
- DC choppers
- AC motor speed control
- UPS Uninterruptable power supplies
- General power switching applications
- Electronic (also portable) welders

¹⁾ T_{case} = 25 °C, unless otherwise specified

²⁾ I_F = -I_C, V_R = 600 V,
-di_F/dt = 1500 A/μs, V_{GE} = 0 V

³⁾ Use V_{GEoff} = -5... -15 V

⁶⁾ The free-wheeling diodes of the GAL type have the data of the inverse diodes.

⁸⁾ CAL = Controlled Axial Lifetime Technology

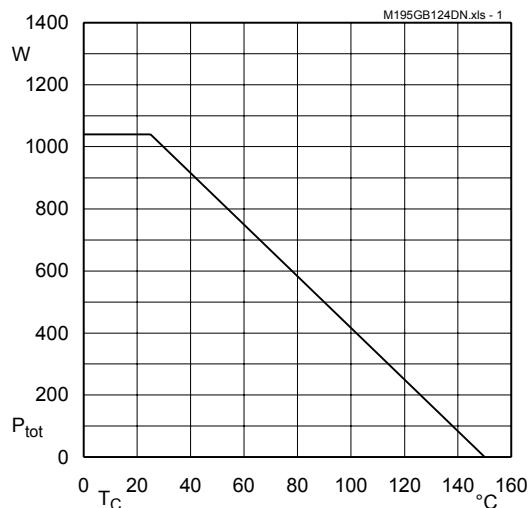


Fig. 1 Rated power dissipation $P_{\text{tot}} = f (T_C)$

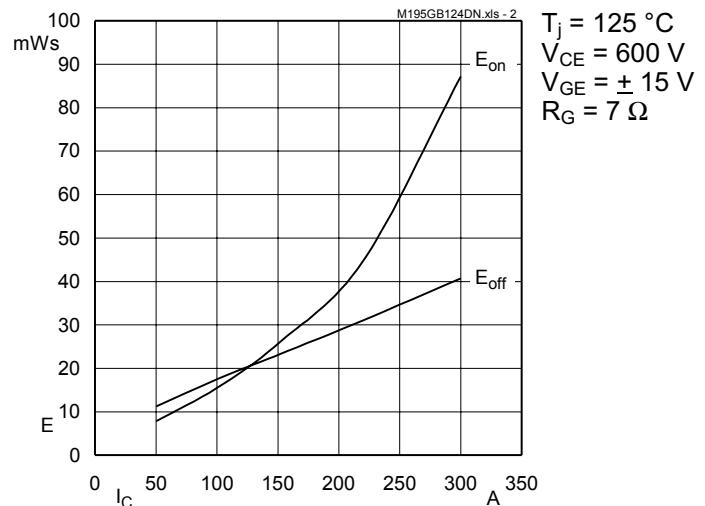


Fig. 2 Turn-on /-off energy = f (I_C)

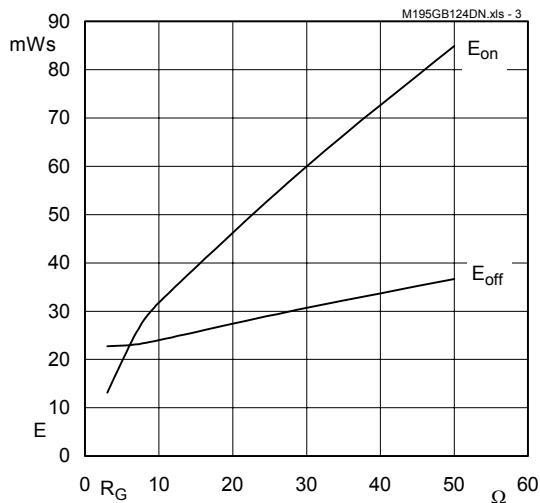


Fig. 3 Turn-on /-off energy = f (R_G)

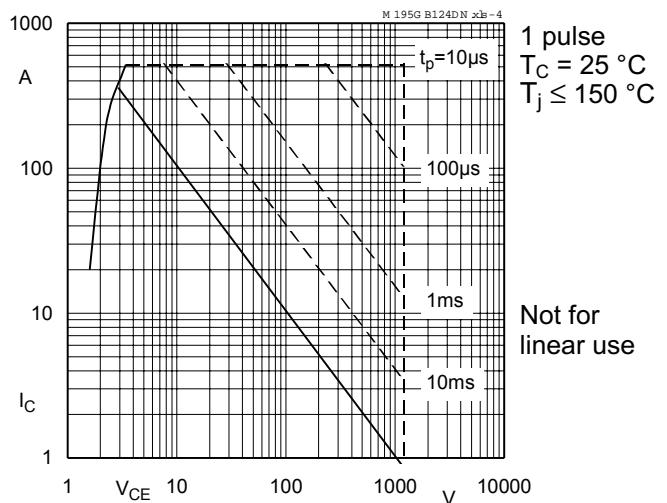


Fig. 4 Maximum safe operating area (SOA) $I_C = f (V_{CE})$

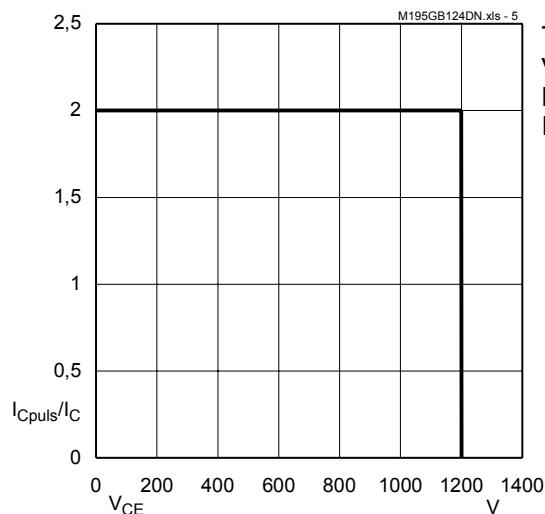


Fig. 5 Turn-off safe operating area (RBSOA)

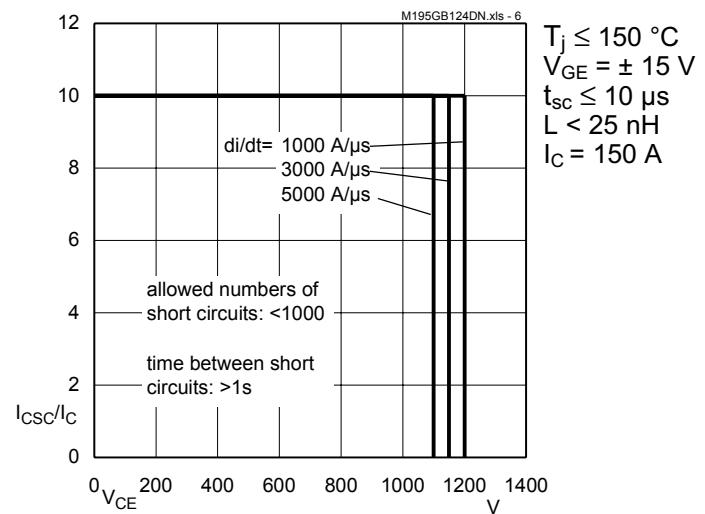


Fig. 6 Safe operating area at short circuit $I_C = f (V_{CE})$

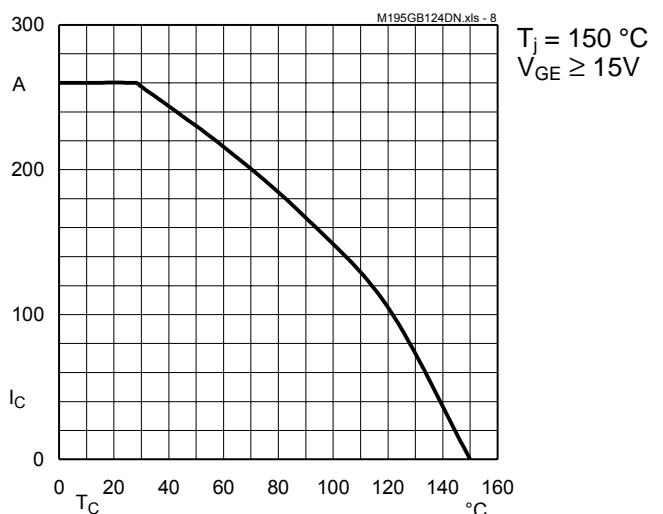


Fig. 8 Rated current vs. temperature $I_C = f (T_C)$

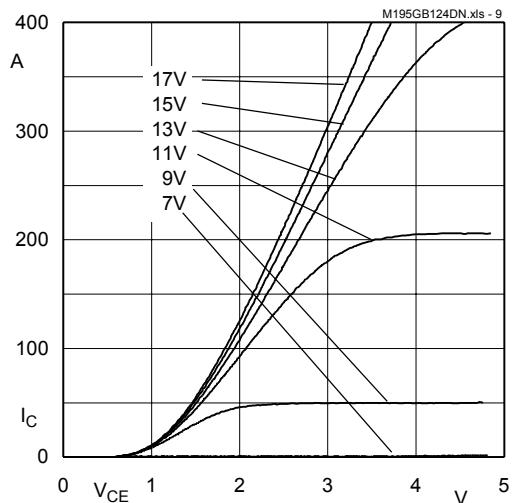


Fig. 9 Typ. output characteristic, $t_p = 80 \mu\text{s}; 25 \text{ } ^\circ\text{C}$

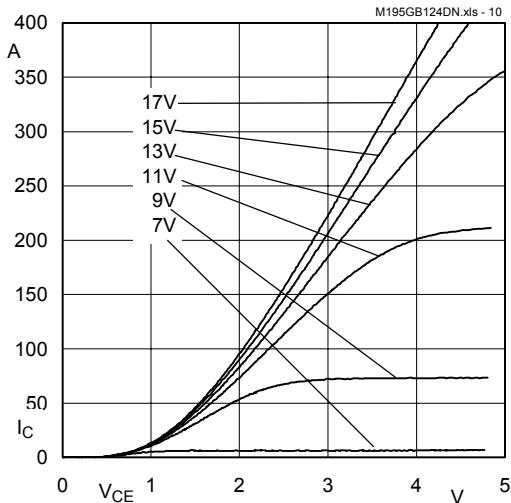


Fig. 10 Typ. output characteristic, $t_p = 80 \mu\text{s}; 125 \text{ } ^\circ\text{C}$

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_{C(t)}$$

$$V_{CEsat(t)} = V_{CE(TO)(Tj)} + r_{CE(Tj)} \cdot I_{C(t)}$$

$$V_{CE(TO)(Tj)} \leq 1,29 + 0,0001 (T_j - 25) [\text{V}]$$

$$\text{typ.: } r_{CE(Tj)} = 0,0061 + 0,000022 (T_j - 25) [\Omega]$$

$$\text{max.: } r_{CE(Tj)} = 0,0077 + 0,000022 (T_j - 25) [\Omega]$$

valid for $V_{GE} = + 15^{+2}_{-1} \text{ [V]}$; $I_C > 0,3 I_{Cnom}$

Fig. 11 Saturation characteristic (IGBT)
 Calculation elements and equations

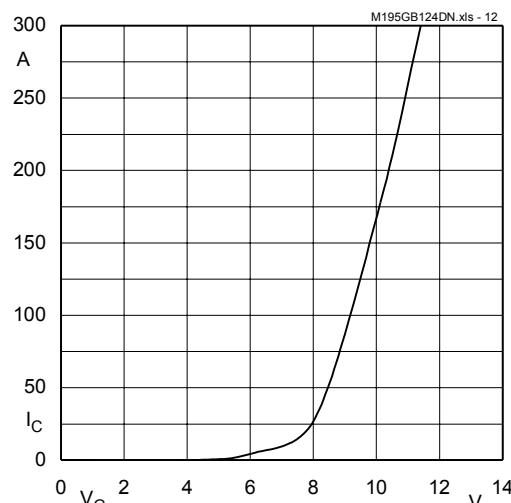


Fig. 12 Typ. transfer characteristic, $t_p = 80 \mu\text{s}; V_{CE} = 20 \text{ V}$

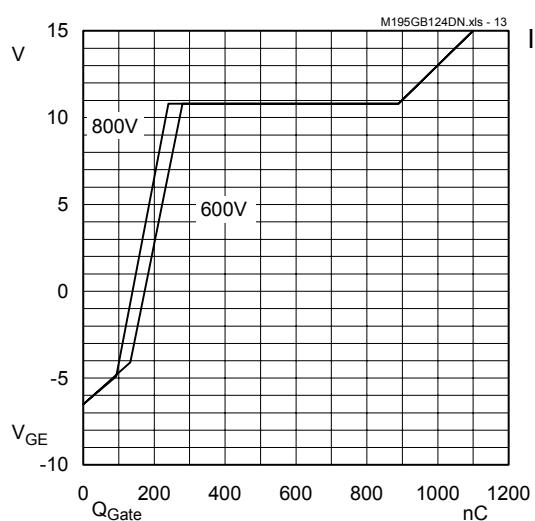


Fig. 13 Typ. gate charge characteristic

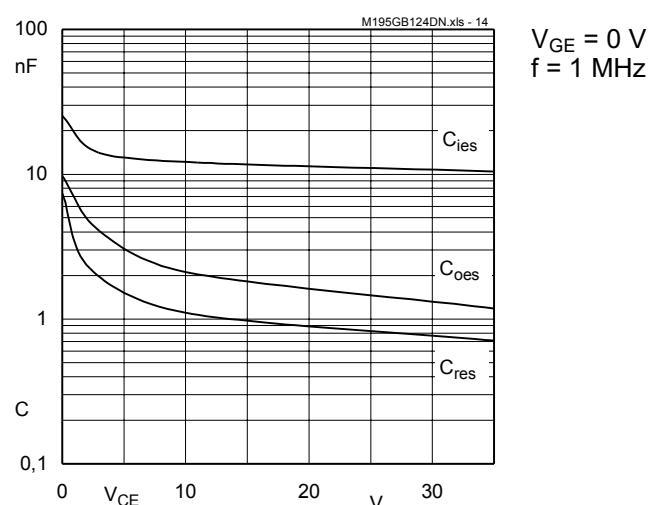


Fig. 14 Typ. capacitances vs. V_{CE}

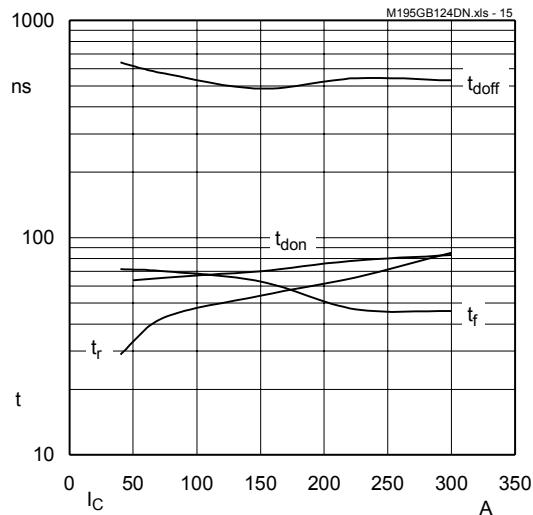


Fig. 15 Typ. switching times vs. I_C

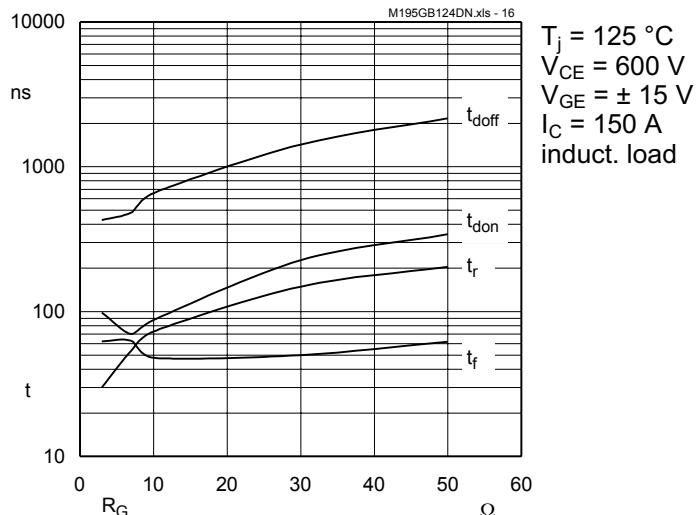


Fig. 16 Typ. switching times vs. gate resistor R_G

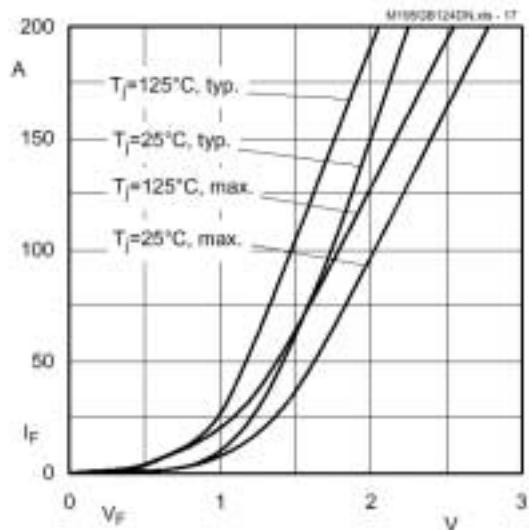


Fig. 17 Typ. CAL diode forward characteristic

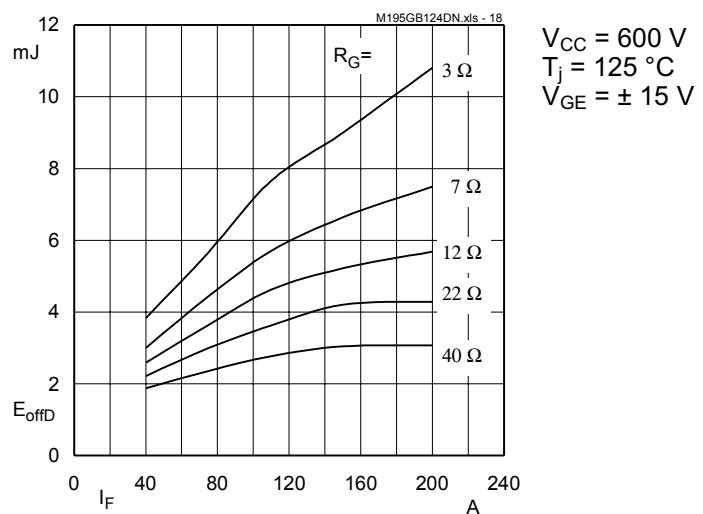


Fig. 18 Diode turn-off energy dissipation per pulse

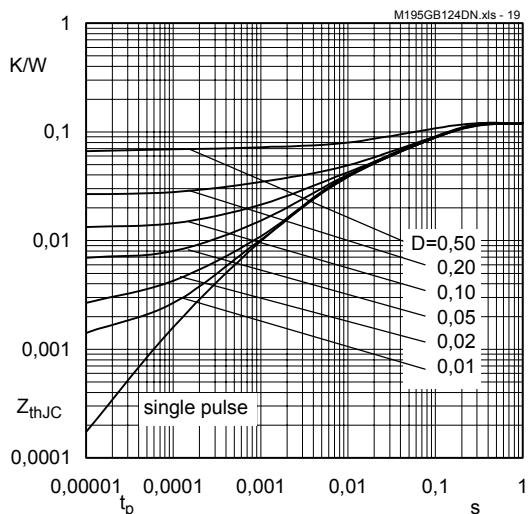


Fig. 19 Transient thermal impedance of IGBT
 $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

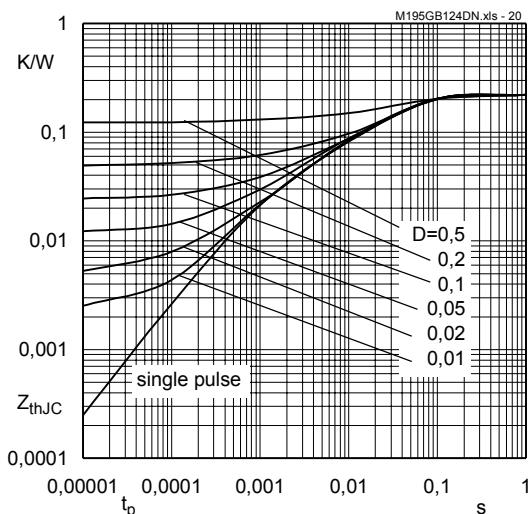


Fig. 20 Transient thermal impedance of
 inverse CAL diodes $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

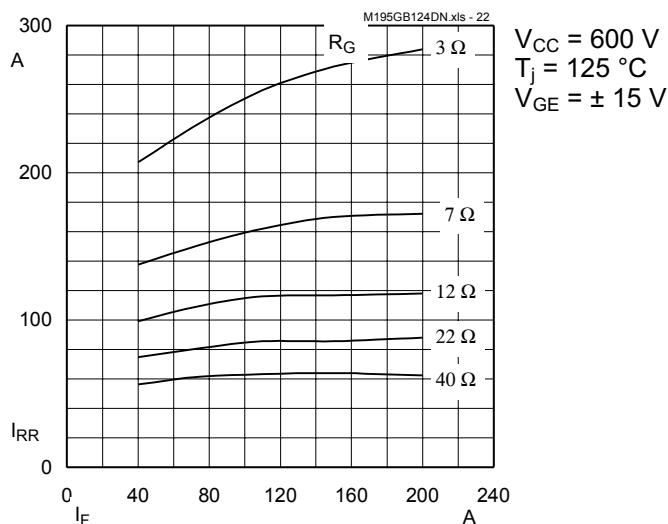


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F; R_G)$

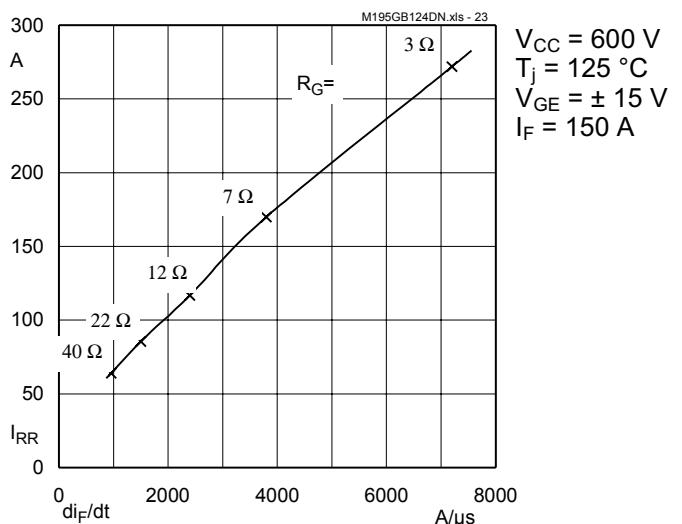


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(di/dt)$

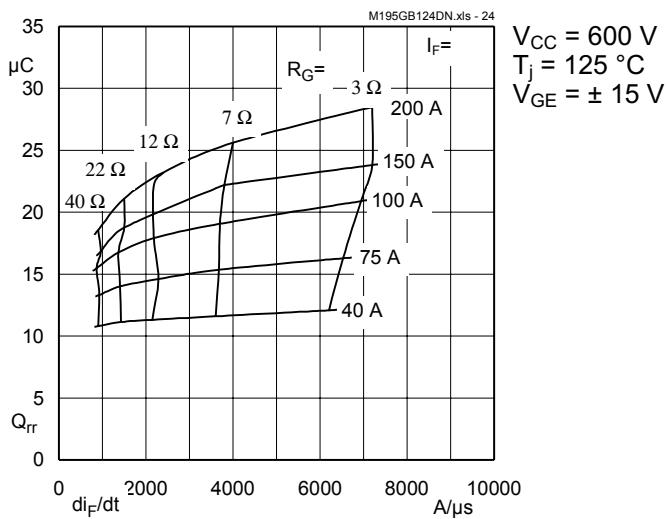


Fig. 24 Typ. CAL diode recovered charge

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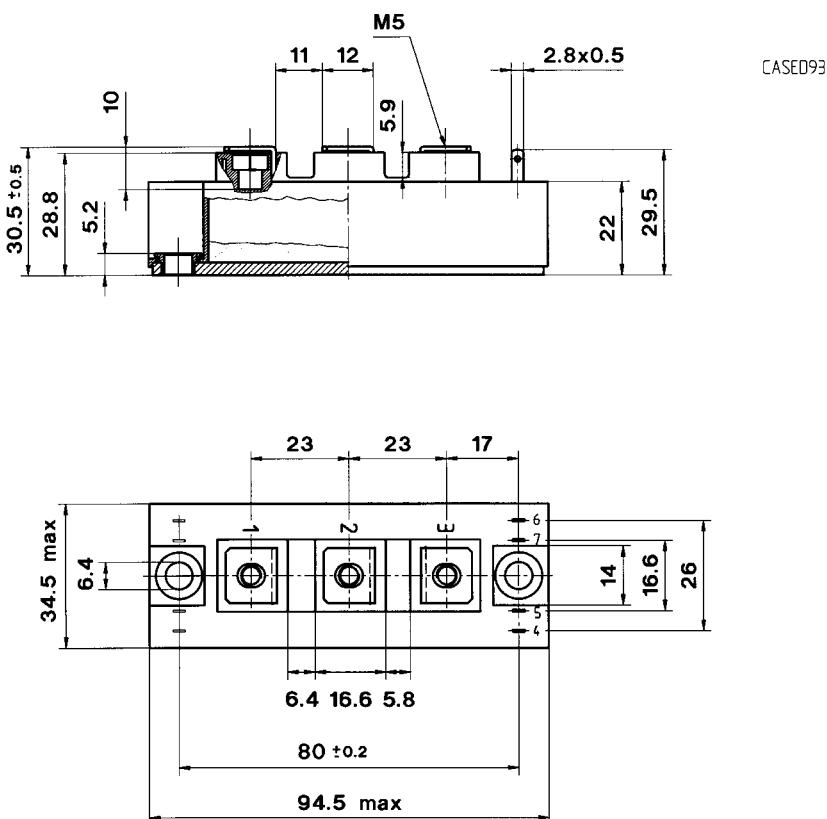
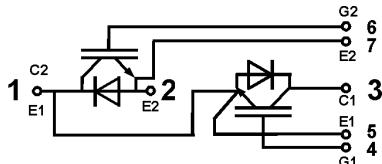
SEMITRANS 2N (low inductance)

Case D 93

UL Recognized

File no. E 63 532

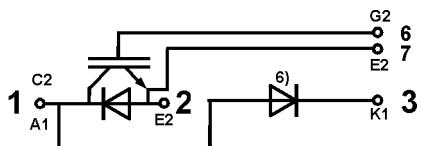
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Dimensions in mm

SKM 195 GAL 124 DN

Case D 94 (→ D 93)



Case outline and circuit diagrams

Mechanical Data		Values	Units	
Symbol	Conditions			
M ₁	to heatsink, SI Units to heatsink, US Units	(M6) 3 27	— 44	Nm lb.in.
M ₂	for terminals, SI Units for terminals, US Units	(M5) 2,5 22	— 44	Nm lb.in.
a		—	5x9,81	m/s ²
w		—	160	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Twenty devices are supplied in one SEMIBOX D without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 2)

Larger packing units of 20 pieces are used if suitable

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